| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|--|------|-----|-----|------|
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$ | - | - | 50 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$ | - | - | 50 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u> | - | - | 30 | mA |
| V _T | on-state voltage | I _T = 5 A; T _j = 25 °C; <u>Fig. 10</u> | - | 1.4 | 1.7 | V |
| Dynamic chara | acteristics | | | | | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 1000 | - | - | V/µs |
| dl _{com} /dt | rate of change of commutating current | V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 4 A; dV_{com}/dt = 20 V/ μ s; (snubberless condition); gate open circuit | 6 | - | - | A/ms |

5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|--------------------------------|--------------------|----------------|
| 1 | T1 | main terminal 1 | | T2——T1 |
| 2 | T2 | main terminal 2 | (7 8 S) | G sym051 |
| 3 | G | gate | | Symost |
| mb | T2 | mounting base; main terminal 2 | DPAK (SOT428) | |

6. Ordering information

Table 3. Ordering information

| Table of ordering morniagen | | | | | | |
|-----------------------------|---------|---|---------|--|--|--|
| Type number | Package | | | | | |
| | Name | Description | Version | | | |
| BTA204S-800B | DPAK | plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped) | SOT428 | | | |

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---------------------|--|--|-----|-----|------|
| V_{DRM} | repetitive peak off-state voltage | | - | 800 | V |
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_{mb} \le 107 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3 | - | 4 | Α |
| I _{TSM} | non-repetitive peak on- state current | full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5 | - | 25 | Α |
| | | full sine wave; T _{j(init)} = 25 °C; t _p = 16.7 ms | - | 27 | Α |
| l ² t | I ² t for fusing | t _p = 10 ms; SIN | - | 3.1 | A²s |
| dl _T /dt | rate of rise of on-state current | I _G = 100 mA | - | 100 | A/µs |
| I _{GM} | peak gate current | | - | 2 | Α |
| P_{GM} | peak gate power | | - | 5 | W |
| P _{G(AV)} | average gate power | over any 20 ms period | - | 0.5 | W |
| T _{stg} | storage temperature | | -40 | 150 | °C |
| Tj | junction temperature | | - | 125 | °C |

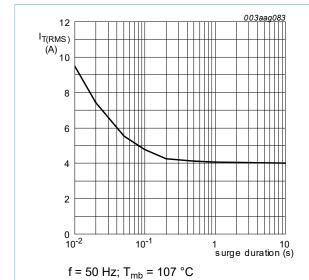


Fig. 1. RMS on-state current as a function of surge duration; maximum values

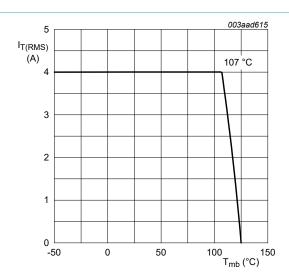


Fig. 2. RMS on-state current as a function of mounting base temperature; maximum values

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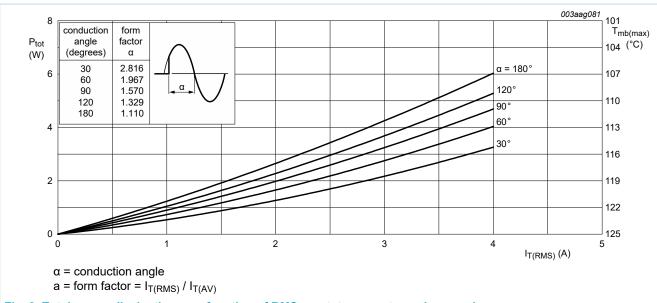


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

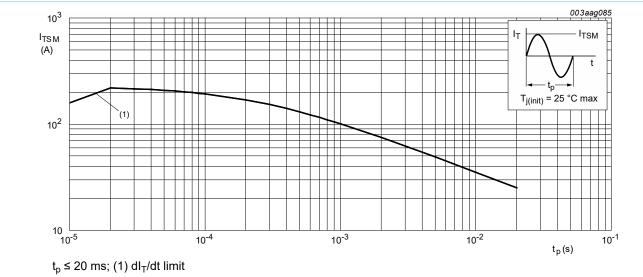


Fig. 4. Non-repetitive peak on-state current as a function of pulse width; maximum values

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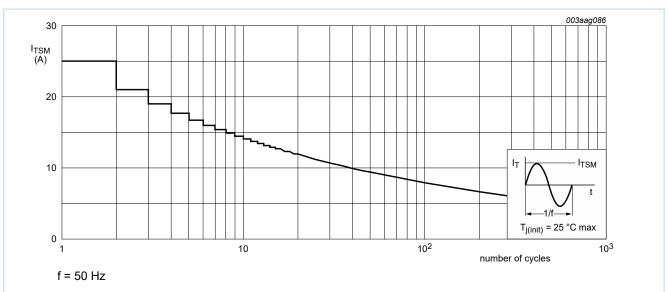
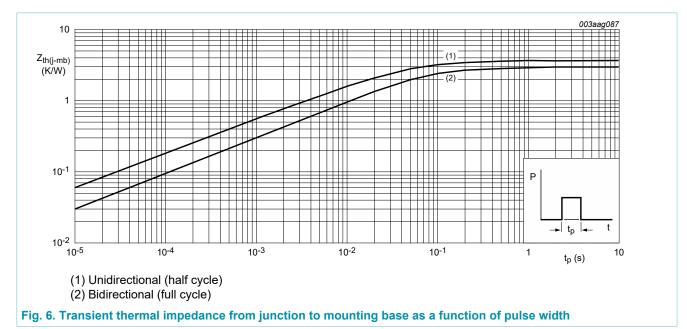


Fig. 5. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

8. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|--|-------------------------------------|-----|-----|-----|------|
| R _{th(j-mb)} | thermal resistance from junction to mounting base | full cycle; Fig. 6 | - | - | 3 | K/W |
| | | half cycle; Fig. 6 | - | - | 3.7 | K/W |
| R _{th(j-a)} | thermal resistance from junction to ambient free air | printed circuit board (FR4) mounted | - | 75 | - | K/W |



9. Characteristics

Table 6. Characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|---------------------------------|---------------------------------------|--|------|-----|-----|------|
| Static char | acteristics | | ' | | | |
| I _{GT} | gate trigger current | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$ | - | - | 50 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 ^{\circ}\text{C}; Fig. 7$ | - | - | 50 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{ G-};$ $T_j = 25 ^{\circ}\text{C}; \underline{\text{Fig. } 7}$ | - | - | 50 | mA |
| I _L latching current | latching current | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 8$ | - | - | 30 | mA |
| | | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 ^{\circ}\text{C}; Fig. 8$ | - | - | 45 | mA |
| | | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 ^{\circ}\text{C}; \text{ Fig. 8}$ | - | - | 30 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u> | - | - | 30 | mA |
| V _T | on-state voltage | I _T = 5 A; T _j = 25 °C; <u>Fig. 10</u> | - | 1.4 | 1.7 | V |
| V_{GT} | gate trigger voltage | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11 | - | 0.7 | 1 | V |
| | | $V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 \text{ °C};$ Fig. 11 | 0.25 | 0.4 | - | V |
| I _D | off-state current | V _D = 800 V; T _j = 125 °C | - | 0.1 | 0.5 | mA |
| Dynamic cl | naracteristics | | | | | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 1000 | - | - | V/µs |
| dl _{com} /dt | rate of change of commutating current | $V_D = 400 \text{ V}; T_j = 125 ^{\circ}\text{C}; I_{T(RMS)} = 4 \text{ A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; (snubberless condition); gate open circuit$ | 6 | - | - | A/ms |

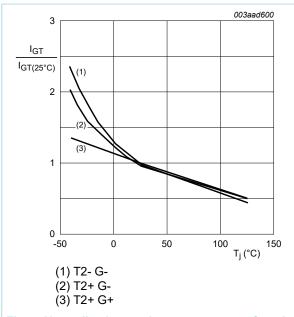


Fig. 7. Normalized gate trigger current as a function of junction temperature

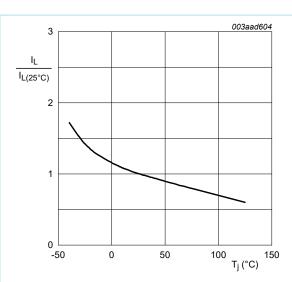


Fig. 8. Normalized latching current as a function of junction temperature

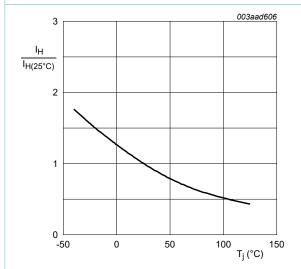
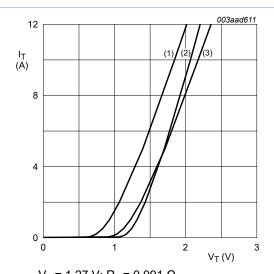


Fig. 9. Normalized holding current as a function of junction temperature



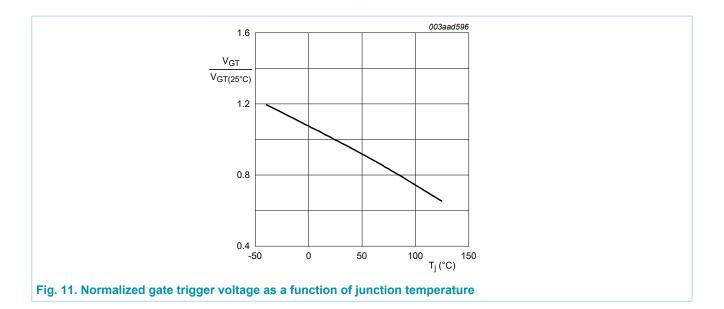
 $\begin{array}{l} \text{V}_{\text{o}} = 1.27 \text{ V}; \text{ R}_{\text{s}} = 0.091 \ \Omega \\ \text{(1)} \text{ T}_{\text{j}} = 125 \ ^{\circ}\text{C}; \text{ typical values} \\ \text{(2)} \text{ T}_{\text{j}} = 125 \ ^{\circ}\text{C}; \text{ maximum values} \\ \text{(3)} \text{ T}_{\text{j}} = 25 \ ^{\circ}\text{C}; \text{ maximum values} \end{array}$

Fig. 10. On-state current as a function of on-state voltage

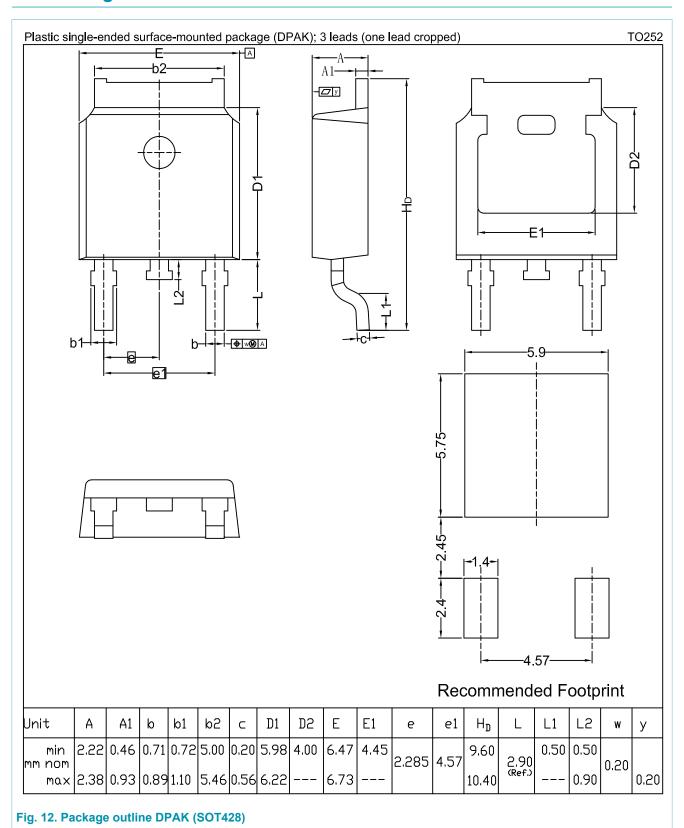
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10. Package outline



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11. Legal information

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| Document status [1][2] | Product status [3] | Definition |
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